

I/CV (I-V, C-V Characterization) Automation Software

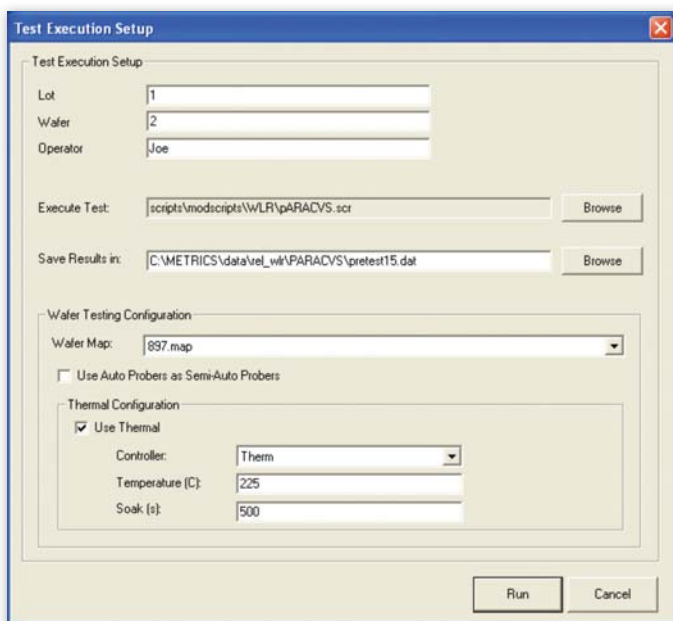
Point. Click. Measure. It's as simple as that.

Metrics™ I/CV provides a Windows XP Professional “wizard-based” operator test environment, test execution and sequencing, along with data logging and post-analysis. Perform I-V and C-V measurements and analysis for design verification, process troubleshooting, reliability engineering, and failure analysis. Metrics I/CV software includes support for semiconductor parameter analyzers, C-V meters, low leakage switch matrices, full and semi-automatic probe stations.

SYSTEM SOFTWARE

Build complete test systems using Metrics I/CV. It is designed to extend the capabilities of existing test and measurement development environments that are used to automate semiconductor characterization measurements on wafer level or packaged devices. The software provides an intuitive platform for developing, editing, and executing complex test plans found in automated lab test systems. Metrics I/CV supports mixed configurations consisting of popular system components from popular test equipment manufacturers:

- Semiconductor parameter analyzers
- CV/LCRZ meters
- Switch matrices
- Wafer probers with thermal chucks
- Power supplies, pulse generators, etc.
(with optional development environment)

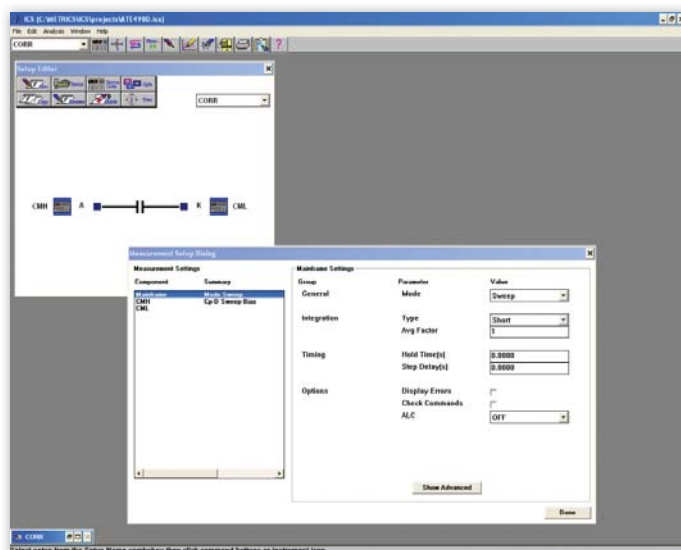


WIZARD OPERATOR SHELL

Test wizards provide step-by-step instructions to the operator when entering runtime information, selecting wafer navigation plans, selecting test plans, and starting a test. Test wizards are conveniently organized and launched from toolbars.

GRAPHICAL ALGORITHM GENERATION

Tests can be generated and edited using the integrated Metrics ICS graphical workspace editor, which allows rapid test development with no programming required.



VISUAL BASIC SCRIPTING

I/CV provides a full-featured script editor with syntax assistance, an interactive test execution environment, and a comprehensive debugger. The user can create VBScripts for the sending low-level GPIB instrument-specific command strings and incorporate test branching and other features within user created algorithms. To simplify test development Metrics Technology also provides an optional Integrated Development Environment (IDE) which includes several libraries of functional APIs that provide access to the I/CV Communication Server, Instrument Drivers, PGU/Oscilloscope Drivers, as well as Thermal and Prober Driver templates. Math function libraries are also included for performing parameter extraction and decision branching. Using the Metrics IDE to create custom algorithms, administrators can create sophisticated test methodologies, but provide just the right level of control for system users.

TEST SEQUENCING TOOLS

Test sequencing tools provide access to a library of built-in software components, supporting all the functions necessary to create a variety of test plans at both Module and Die level. The script editor provides a “wizard-based” interface for building a test script so the user does not have to learn complicated command syntax or spend time debugging mistyped commands. Components include:

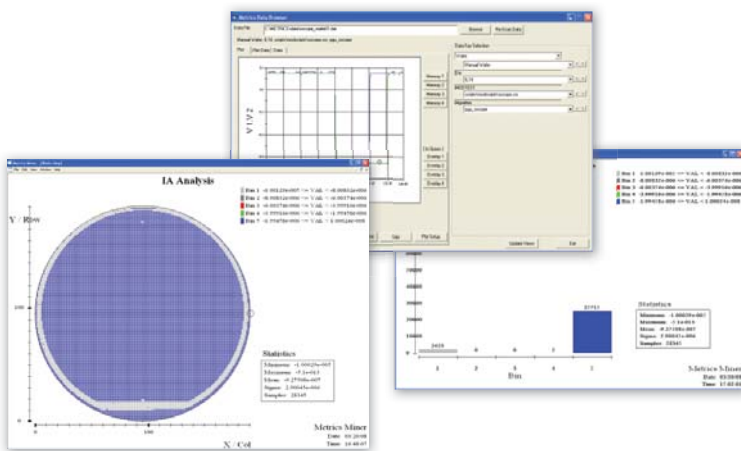
- Automated sub-die prober movement
- Executing a switch connection
- Executing a test algorithm

AUTO-ANALYSIS AND REPORTING

Data analysis tools included for extracting parametric quantities from the test data and generating several standard reports and graphs, including:

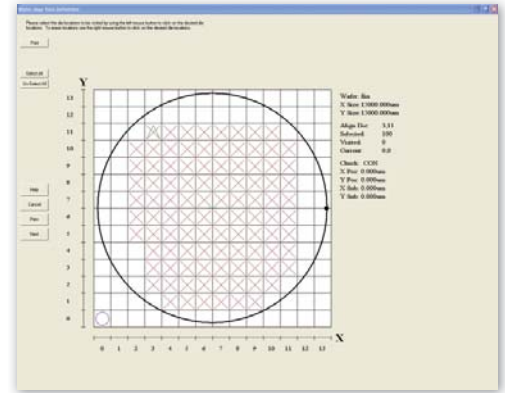
- Color wafer maps
- Histograms
- Parameter statistics
- Parametric values vs. die location
- Tables of I-V or C-V raw data

These tools can also be installed on a second PC to allow the analysis of data without interfering with data collection.



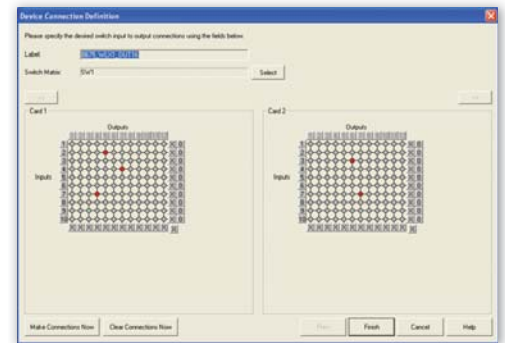
WAFER PROBE NAVIGATION

Wafer probe navigation control provides support for most popular semi-automatic and automatic probe stations. The user can define probe plans including sub-die movement for performing automated test of multiple modules or individual devices across a wafer. Latest support for vision correction capabilities of the Cascade Nucleus and Suss MicroTec ProberBench software packages has been included.



SWITCH MATRIX CONTROL

Interactive switch matrix control allows the selection of cross-point connections between test instruments and device pins. It automates the execution of multiple connections when using a probe card to make contact to multiple devices on a wafer. Drivers are available for many popular switch matrixes, supporting multiple switch mainframes and a variety of switch matrix and multiplexer cards.



SOFTWARE CUSTOMIZATION (Optional)*

- Customization of operator interfaces to Metrics I/CV software.
- Development of instrument, switch, probe, thermal chucks, and other custom instrument drivers.
- Creation of custom measurement algorithms used in test scripts, including measurement setups, parameter extractions, and custom analysis.

TRAINING (Optional)

Training is available from Metrics Technology at the customer site. This service is optional and requires the purchase of a training course.

* Provided by quotation (NRE charges apply)

INTEGRATED DEVELOPMENT ENVIRONMENT (Optional)

	Annual License	Perpetual License
License Period	1 year	Does not expire - runs only on supported OS and PC configurations at time of purchase
Support Type	Phone/Email	Email only
Test Algorithms	ICS Examples NVM Test Algorithms WLR Test Algorithms CV Algorithms VB Script and Thermal Drivers (includes VB source code license)	ICS Examples Only NVM Test Algorithms WLR Test Algorithms CV Algorithms VB Script and Thermal Drivers (includes VB source code license)
Upgrades	All new features as they are added	Fixes Only

For more information visit our website at www.metricstech.com or call us at 505-761-9630.